
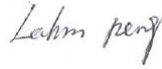



EN 55024: 1998+A1: 2001+A2: 2003**Measurement and Test Report****For****Smart Zone Technology Limited****8/F., Tower 1, Tern Centre, 237 Queen`s Road, Central.HK**

Report Concerns: Original Report	Equipment Type: AC/DC ADAPTOP
Model:	<u>SZ-ACDC</u>
Report No.:	<u>STR11078225E-2</u>
Test Date:	<u>2011-08-01 to 2011-08-03</u>
Issue Date:	<u>2011-08-03</u>
Tested By:	<u>Jason Jiang / Engineer</u> 
Reviewed By:	<u>Lahm Peng / EMC Manager</u> 
Approved & Authorized By:	<u>Jandy so / PSQ Manager</u> 
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Note: This test report is limited to the above client company and the product model only. It may not be duplicated without prior permitted by SEM.Test Compliance Service Co., Ltd.

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1. GENERAL INFORMATION

1.1 Product Description for Equipment Under Test (EUT)

Client Information

Applicant: Smart Zone Technology Limited
Address of applicant: 8/F., Tower 1, Tern Centre, 237 Queen`s Road, Central.HK

Manufacturer: Shenzhen Smart Team Technology Limited
Address of manufacturer: 3^{DR} Floor, Xutai Industrial, Longwo Road, Longtian Village, Keng Zi Residential, Ping Shan.

General Description of E.U.T

Items	Description
EUT Description:	AC/DC ADAPTOP
Trade Name:	Smartzone, Dailypower
Model No.:	SZ-ACDC
Rated Voltage:	AC 230V/50Hz
Rated Current	0.8A
For more information refer to the circuit diagram form and the user`s manual.	

The test data is gathered from a production sample, provided by the manufacturer.

1.2 Test Standards

The following report is prepared on behalf of the Smart Zone Technology Limited in accordance with EN55024, Immunity characteristics Limits and methods of measurement.

The objective of the manufacturer is to demonstrate compliance with EN55024, Immunity characteristics Limits and methods of measurement.

Maintenance of compliance is the responsibility of the manufacturer. Any modification of the product maybe which result in lowering the emission/immunity should be checked to ensure compliance has been maintained

1.3 Test Methodology

All measurements contained in this report were conducted with EN55024, Immunity characteristics Limits and methods of measurement.

The equipment under test (EUT) was configured to measure its highest possible emission/immunity level. The test setup was adapted accordingly in reference to the Operating Instructions.

1.4 Test Facility

- **CNAS Registration No.: L4062**

Shenzhen SEM.Test Electronics Service Co., Ltd. is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L4062. All measurement facilities used to collect the measurement data are located at 3/F, Jinbao Commerce Building, Xin'an Fanshen Road, Bao'an District, Shenzhen, P.R.C (518101)

1.5 EUT Exercise Software

The EUT exercise program used during radiated and conducted testing was designed to exercise the system components. The test software, provided by the customer, is started while the EUT is on to simulate the normal work. under the Windows XP terminal.

1.6 Accessories Equipment List and Details

Description	Manufacturer	Model	Serial Number
/	/	/	/

1.7 EUT Cable List and Details

Cable Description	Length (M)	Shielded/Unshielded	With Core/Without Core
/	/	/	/

1.8 Performance Criteria

All the test data has been collected, reduced, and analyzed within this report in accordance with Immunity requires the following as specific performance criteria:

- A. The apparatus shall continue to operate as intended during and after the test. The manufacturer specifies some minimum performance level. The performance level may be specified by the manufacturer as a permissible loss of performance.
- B. The apparatus shall continue to operate as intended after the test. This indicates that the EUT does not need to function at normal performance levels during the test, but must recover. Again some minimal performance is defined by the manufacture. No change in operating state or loss or data is permitted.
- C. Temporary loss of function is allowed. Operation of the EUT may stop as long as it is either automatically reset or can be manually restored by operation of the controls.

2. SUMMARY OF TEST RESULTS

Description of Test	Result
Electrostatic Discharge Immunity (ESD) in accordance with IEC 61000-4-2	Compliant
Radiated RF-Electromagnetic Field Immunity in accordance with IEC 61000-4-3	Compliant
Electrical Fast Transient/Burst (EFT/B) immunity in accordance with IEC 61000-4-4	Compliant
Surge immunity test immunity in accordance with IEC 61000-4-5	Compliant
Immunity to conducted disturbances in accordance with IEC 61000-4-6	Compliant
Voltage Dips/Interruptions immunity test in accordance with IEC 61000-4-11	Compliant

3. Electrostatic Discharge Immunity (ESD)

3.1 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
ESD Generator	TESQ AG	NSG 437	161	2010-12-20	2011-12-19

3.2 Test Procedure

Test is conducting under the description of IEC 61000-4-2.

Test Performance

Performance Criterion: B

Environmental Conditions

Temperature:	26 °C
Relative Humidity:	55%
ATM Pressure:	1011 mbar

3.3 EN61000-4-2: Electrostatic Discharge Immunity Test Data

Table 1: Electrostatic Discharge Immunity (Air Discharge)

EN 61000-4-2 Test Points	Test Levels (kV)									
	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
Slots	A	A	A	A	A	A	B	B		
Port	A	A	A	A	A	A	B	B		

Table 2: Electrostatic Discharge Immunity (Direct Contact)

EN 61000-4-2	Test Levels (kV)									
Test Points	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
N/A	/	/	/	/						

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)

EN 61000-4-2	Test Levels (kV)									
Test Points	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
Front Side	A	A	A	A						
Top Side	A	A	A	A						
Back Side	A	A	A	A						
Left Side	A	A	A	A						
Right Side	A	A	A	A						

Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)

EN 61000-4-2	Test Levels (kV)									
Test Points	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
Front Side	A	A	A	A						
Top Side	A	A	A	A						
Back Side	A	A	A	A						
Left Side	A	A	A	A						
Right Side	A	A	A	A						

Test Result: Pass

4. Continuous Radiated Disturbances

4.1 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Signal Generator	Rohde & Schwarz	SMT03	100059	2010-12-20	2011-12-19
Voltage Probe	Rohde & Schwarz	URV5-Z2	100013	2010-12-20	2011-12-19
Power Amplifier	AR	150W1000	300999	2010-12-20	2011-12-19
Power Amplifier	AR	25S1G4AM1	305993	2010-12-20	2011-12-19
Trilog Antenna	SCHWARZBECK	VULB9163	9163-333	2011-01-09	2012-01-08
Anechoic chamber	Albatross Projects	MCDC	----	2010-03-20	2012-03-19

4.2 Test Procedure

Test is conducting under the description of IEC 61000-4-3.

Test Performance

Performance Criterion: A

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	52%
ATM Pressure:	1010 mbar

4.3 EN61000-4-3: Continuous Radiated Disturbances Test Data

Frequency step: 1% of fundamental

Dwell time: 1 second

Frequency Range (MHz)	Front (3 V/m)		Rear (3 V/m)		Left Side (3 V/m)		Right Side (3 V/m)	
	VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	A	A	A	A	A	A	A	A

Test Result: Pass

5. Electrical Fast Transients

5.1 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Transient 2000	EMC PARTNER	TRA2000	863	2010-12-20	2011-12-19
Couple Clamp	EMC PARTNER	CN-EFT1000	513	2010-12-20	2011-12-19

5.2 Test Procedure

Test is conducting under the description of IEC 61000-4-4.

Test Performance

Performance Criterion: B

Environmental Conditions

Temperature:	22 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

5.3 EN61000-4-4: Electrical Fast Transients Test Data

EN 61000-4-4		Test Levels (kV)							
Test Points		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
Power Supply Power Line of EUT	L1	B	B	B	B	/	/	/	/
	L2	B	B	B	B	/	/	/	/
	Earth	/	/	/	/	/	/	/	/
	L1+L2	B	B	B	B	/	/	/	/
	L1 + Earth	/	/	/	/	/	/	/	/
	L2 + Earth	/	/	/	/	/	/	/	/
	L1+L2+Earth	/	/	/	/	/	/	/	/
Signal ports		/	/	/	/	/	/	/	/

Test Result: Pass

6. Surge

6.1 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Transient 2000	EMC PARTNER	TRA2000	863	2010-12-20	2011-12-19
Couple Clamp	EMC PARTNER	CN-EFT1000	513	2010-12-20	2011-12-19

6.2 Test Procedure

Test is conducting under the description of IEC 61000-4-5.

Test Performance

Performance Criterion: B

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

6.3 EN61000-4-5: Surge Test Data

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	L-N	A	/
2	1kV	±	L-N	B	/
3	2kV	±	L-PE, N-PE	/	/
4	4kV	±	L-N, L-PE, N-PE	/	/

Test Result: Pass

7. Continuous Conducted Disturbances

7.1 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Immunity simulator	EMTEST	MV500	0800-44	2010-12-20	2011-12-19

7.2 Test Procedure

Test is conducting under the description of IEC 61000-4-6.

Test Performance

Performance Criterion: A

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

7.3 EN61000-4-6: Continuous Conducted Disturbances Test Data

Sweep frequency range: 150kHz~80MHz

Frequency step: 1% of fundamental

Dwell time: 1 second

Level	Voltage Level (e.m.f.) U_0	Modulation:	Pass	Fail
1	1	AM 80%, 1kHz sinewave	/	/
2	3	AM 80%, 1kHz sinewave	A	/
3	10	AM 80%, 1kHz sinewave	/	/
X	Special	/	/	/

Test Result: Pass

8. Voltage Dips And Interruptions

8.1 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Transient 2000	EMC PARTNER	TRA2000	863	2010-12-20	2011-12-19
Couple Clamp	EMC PARTNER	CN-EFT1000	513	2010-12-20	2011-12-19

8.2 Test Procedure

Test is conducting under the description of IEC 61000-4-11.

Test Performance

Performance Criterion: B/C

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	50%
ATM Pressure:	1011 mbar

8.3 EN61000-4-11: Voltage Dips And Interruptions Test Data

Level	U2	td	Phase Angle	N	Pass	Fail
1	>95%	10ms	0/90/180/270	3	A	/
2	30%	500ms	0/90/180/270	3	B	/
3	>95%	5000ms	0/90/180/270	3	C	/

Test Result: Pass

EXHIBIT 1- PRODUCT LABELING

Proposed CE Label Format



Specifications: Text is Black in color and is right justified. Labels are printed in indelible ink on permanent adhesive backing or silk-screened onto the EUT and the user manual.

Proposed Label Location on EUT

CE Label Location



EXHIBIT 2 - EUT PHOTOGRAPHS

EUT View 1



EUT View 2



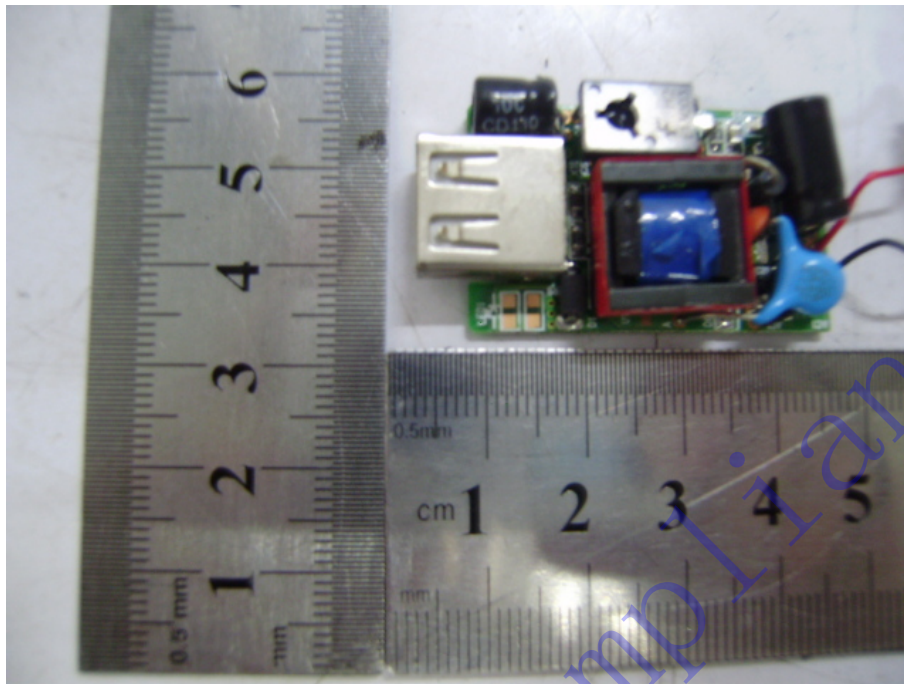
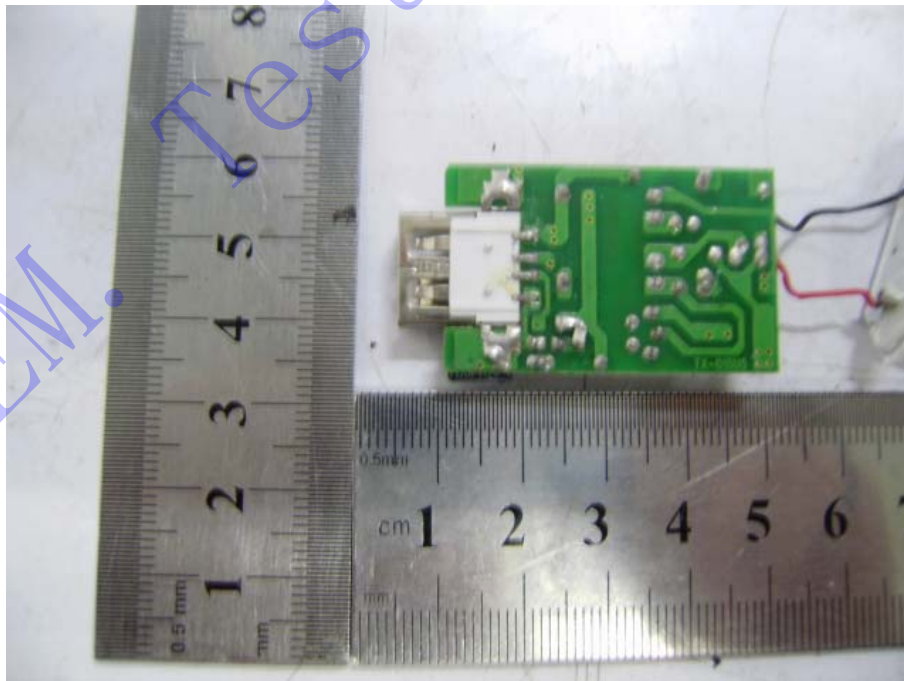
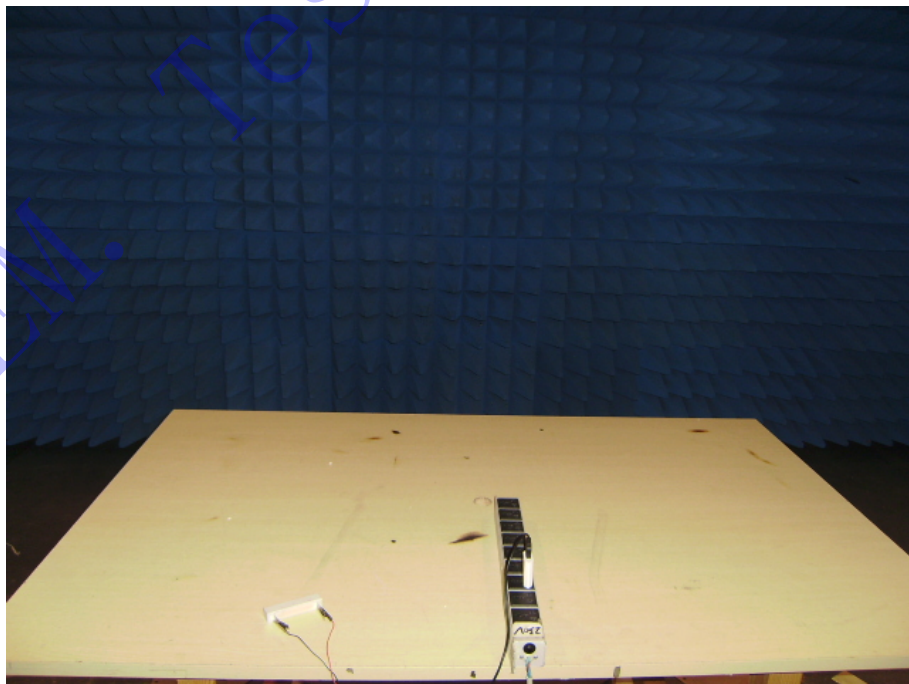
Solder Board-Component View 1**Solder Board-Component View 2**

EXHIBIT 3 - TEST SETUP PHOTOGRAPHS

IEC 61000-4-2



IEC 61000-4-3



IEC 61000-4-4/-5/-11**IEC 61000-4-6**

EXHIBIT 4 - SCHEMATICS

EXHIBIT 5 - USERS MANUAL

******* END OF REPORT *******